

## FORM PTO 1449 (Modified)

LIST OF PATENTS AND  
PUBLICATIONS FOR  
APPLICANT'S INFORMATION  
DISCLOSURE STATEMENTPage 1 of 5

ATTY. DOCKET NO. EI-2-04-003

SERIAL NO.

N/A

APPLICANT R. Japp et al

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## U. S. PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
TW	AA	3,953,566	04/76	Gore			
	AB	3,962,653	06/76	Basset			
	AC	4,187,390	02/80	Gore			
	AD	4,482,516	11/84	Bowman et al			
	AE	4,579,772	04/86	Bhatt et al			
	AF	4,642,160	02/87	Burgess			
	AG	4,675,789	06/87	Kuwabara et al			
	AH	4,713,137	12/87	Sexton			
	AI	4,783,345	11/88	Kleeberg et al			
	AJ	4,864,722	09/89	Lazzarini et al			
	AK	5,129,142	07/92	Bindra et al			
TW	AL	5,229,550	07/93	Bindra et al			

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
	AM						
	AN						
	AO						
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EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
<i>TM</i>	AA	5,246,817	09/93	Shipley			
	AB	5,368,921	11/94	Ishii et al			
	AC	5,376,453	12/94	von Gentzkow et al			
	AD	5,418,689	05/95	Alpaugh et al			
	AE	5,483,101	01/96	Shimoto et al			
	AF	5,565,267	10/96	Capote et al			
	AG	5,648,171	07/97	von Gentzkow et al			
	AH	5,652,055	07/97	King et al			
	AI	5,670,262	09/97	Dalman			
	AJ	5,677,045	10/97	Nagai et al			
	AK	5,685,070	11/97	Alpaugh et al			
<i>TM</i>	AL	5,726,863	03/88	Nakayama et al			

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## U. S. PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
TW	AA	5,814,405	09/98	Branca et al			
	AB	5,981,880	11/99	Appelt et al			
	AC	6,018,196	01/00	Noddin			
	AD	6,042,685	03/00	Shinada et al			
	AE	6,119,338	09/00	Wang et al			
	AF	6,143,401	11/00	Fischer			
	AG	6,207,595 B1	03/01	Appelt et al			
	AH	6,212,769 B1	04/01	Boyko et al			
	AI	6,248,959 B1	06/01	Sylvester			
	AJ	6,291,779 B1	09/01	Lubert et al			
	AK	6,323,436 B1	11/01	Hedrick et al			
	AL	6,378,201 B1	04/02	Tsukada et al			

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EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILI NG
TJN	AA	6,405,431 B1	06/02	Shin et al			
	AB	6,506,979 B1	01/03	Shelnut et al			
	AC	6,541,589 B1	04/03	Baillie			
	AD	6,586,687 B2	07/03	Lee et al			
	AE	US2002/0150673	10/02	Thorn et al			
	AF	US2002/0170827	11/02	Furuya			
	AG	US2002/0172019	11/02	Suzuki et al			
	AH	US2002/0190378	12/02	Hus et al			
TJN	AI	US2003/0022013	01/03	Japp et al			
	AJ						
	AK						
	AL						

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
TJN	AM	JP 56049271	05/81	Japan			Abstract
I	AN	JP 7086710	03/95	Japan			Abstract
	AO	JP 7097466	04/95	Japan			Abstract
TJN	AP	JP 8092394	04/96	Japan			Abstract

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EXAMINER INITIALS		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLAT
TW	AM	JP2001015912A2	01/01	Japan			Abstract
TW	AN	JP2002223070A2	08/02	Japan			Abstract
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	AP						

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